

High Performance Low Complexity DCT-based Iris Recognition

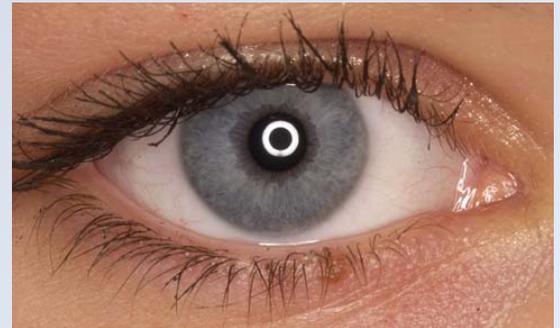
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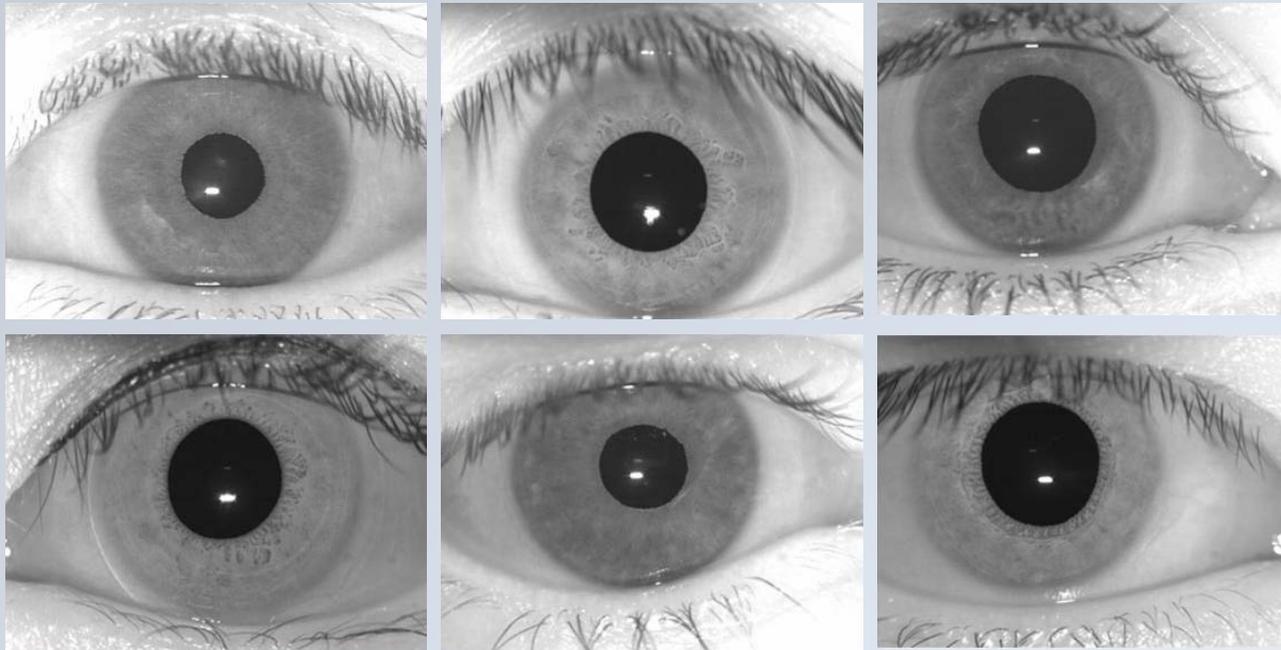
NIST FRGC ICE Workshop 23 March 2006

Outline

- Data Collection
- Iris Recognition System
- Feature Extraction & Weighting
- Classifier Design
- Proposed Metric
- Results
- Ongoing & Future Work



Bath Iris Image Database

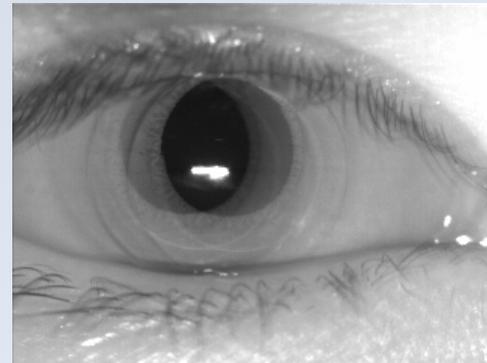
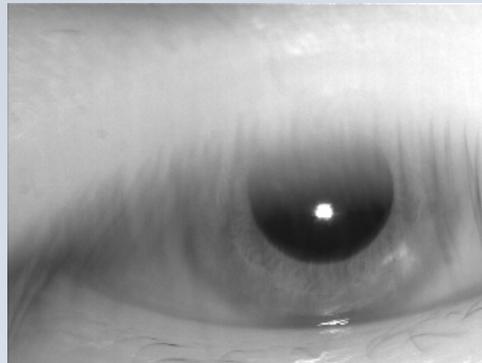
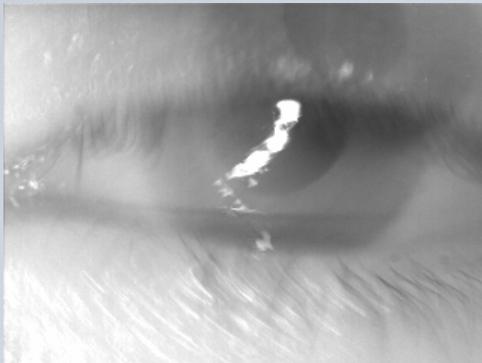
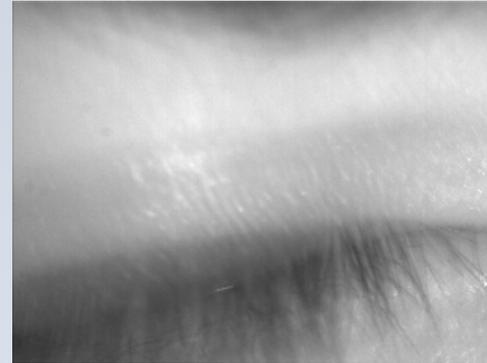
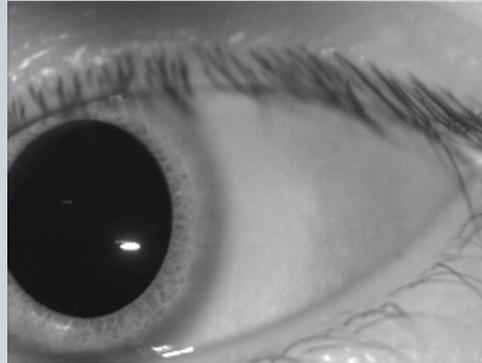


**Currently 16,000 Images
from 400 Subjects (800 Eyes)**

**Mid-2006 Target 32,000 Images
from 800 Subjects (1600 Eyes)**

<http://www.bath.ac.uk/elec-eng/pages/sipg/irisweb>

Non Ideal Images

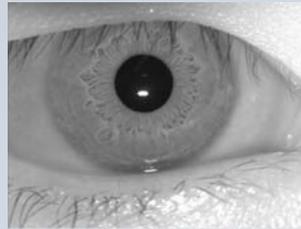


Blinking, Out-of-focus, Motion Blur, Out of Line-of-sight

Iris Recognition System



Image Acquisition
→

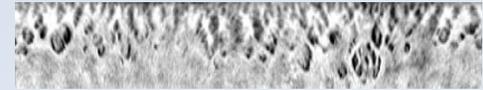


Eye Image

Localization
Normalization
→



Intensity Enhanced
↓



Feature Extraction
↓



Iris Code

Decision

← Match

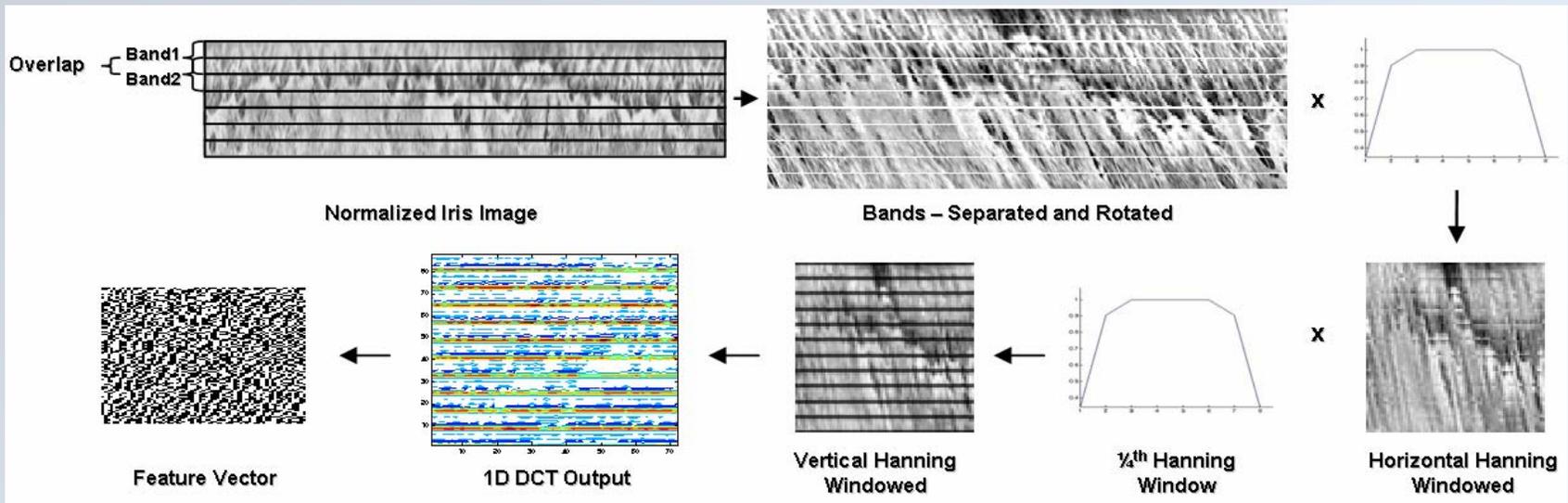
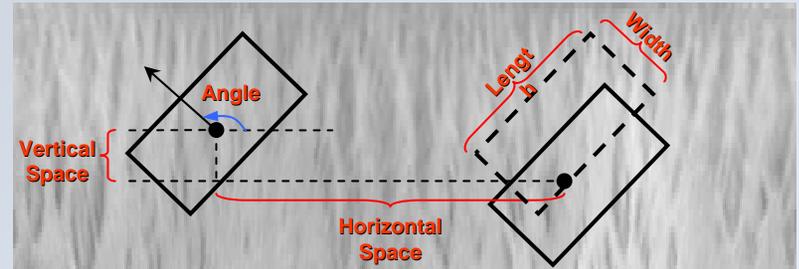
Classifier

←

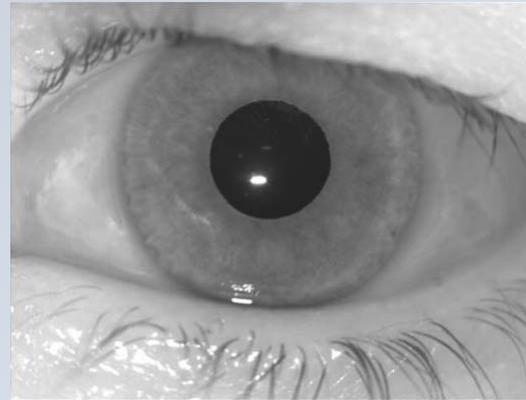
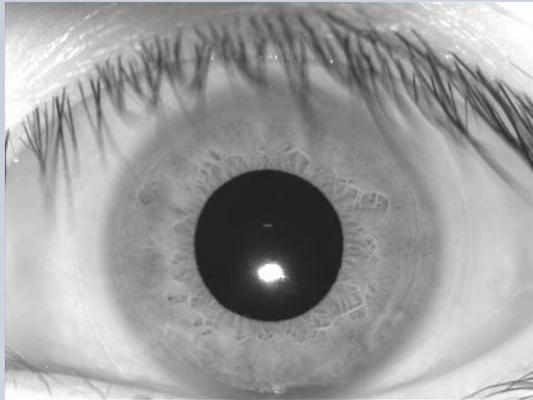
Enrolled Database
↑

Feature Extraction

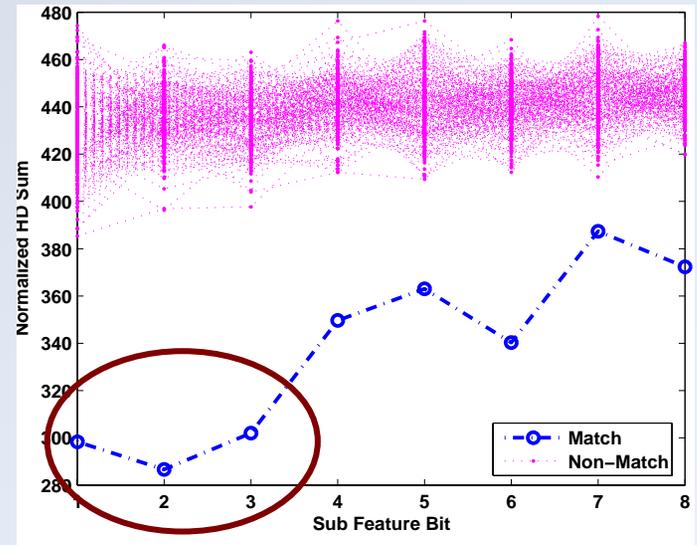
- Image divided in diagonal 8 x 12 patches [BMVA 04, ICIP 05]
- 50% overlap in both directions
- Windowed average over width
- Windowed 1D DCT of length 12 over length
- Adjacent DCTs differenced
- Zero Crossings form Feature Vector



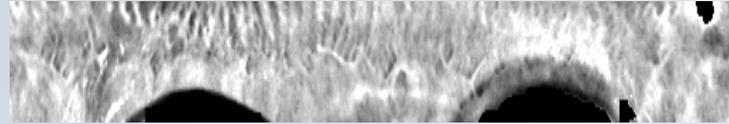
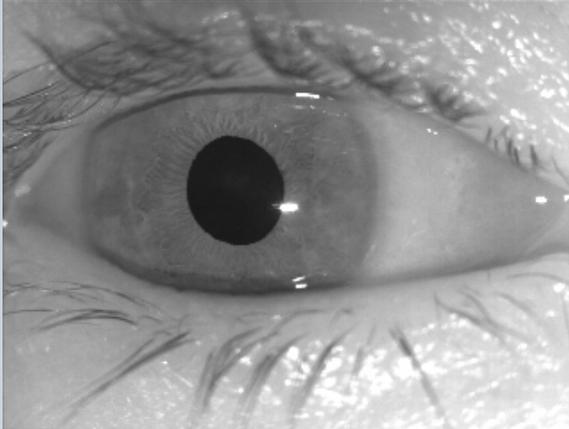
Weighting



- Blue and Brown Iris Structures differ.
- Positional weightings effective within ethnic groups but ineffective across groups.
- DCT Coefficient weighting is effective in choosing the most discriminating bits and reducing the Feature Vector Size.
- Most effective sub-feature bits 1, 2, 3.
- Final Feature Size = 2343 bits (300 bytes).



Masking

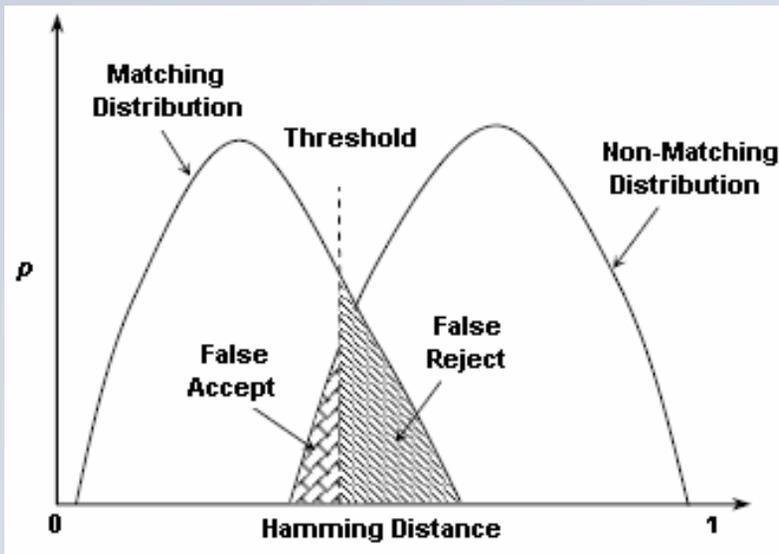


- **Artifacts in iris images lead to erroneous code formation.**
- **Caused by specular reflections, hard contact lens, eyelids, eyelashes, etc.**
- **Non-iris regions masked to 0 graylevel in normalized image.**
- **Masked regions omitted during image equalization and coding.**

Product-of-Sum Distance Classifier

$$Dist = \frac{1}{K} \prod_{i=1}^M \left(\frac{\sum_{j=1}^N (Feature\ 1_{ij} \oplus Feature\ 2_{ij})}{\sum_{j=1}^N (Mask\ 1_{ij} \square Mask\ 2_{ij})} \right)$$

The Product of Sum of Hamming Distances (HD) between subfeature bits gives a metric with good separation of Matching and Non-Matching classes.

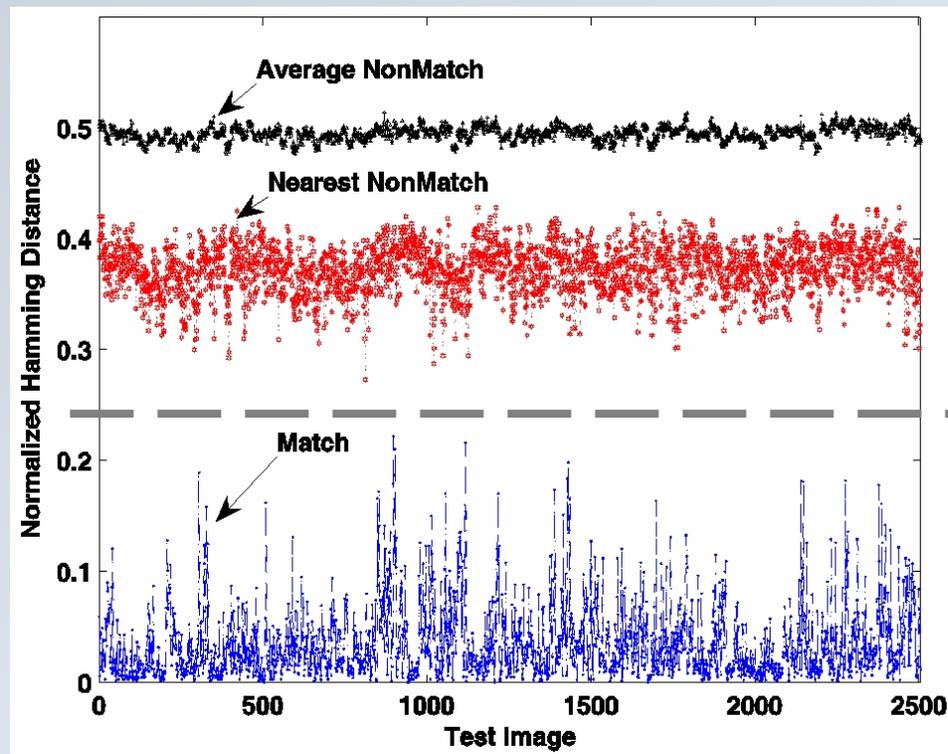


- Parameter Optimization by minimizing Equal Error Rate (EER).
- Theoretical EER predicted by measuring areas of equal overlapped regions.
- Matching and Nearest Non-Matching Distances modelled using best fit distribution curves.

Proposed Metric

A widely used metric for system performance - separation between Normalized Hamming Distance of Matching and **Average** of Non-Matching Irises.

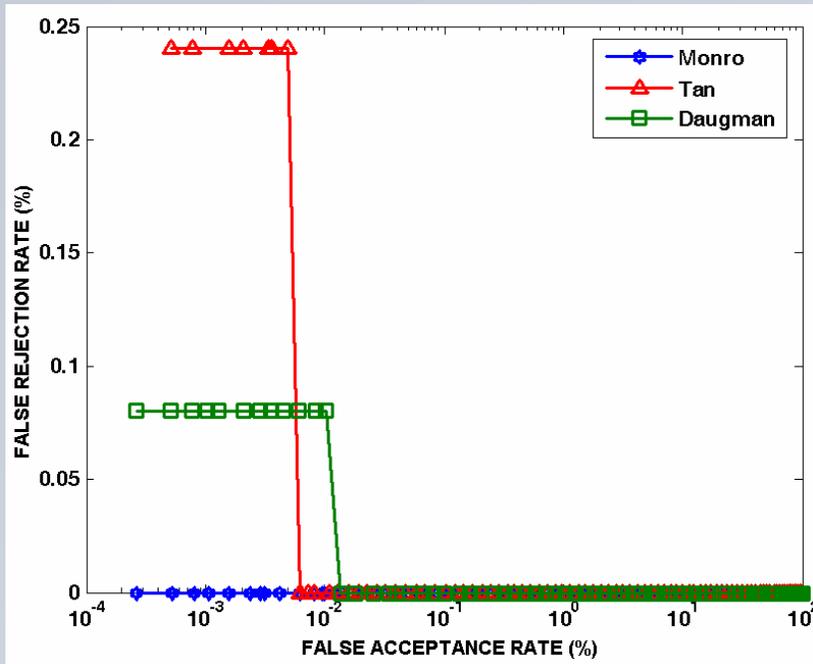
Proposal - Compare the separation between Normalized Hamming Distance of Matching with **Nearest** Non-Matching Irises.



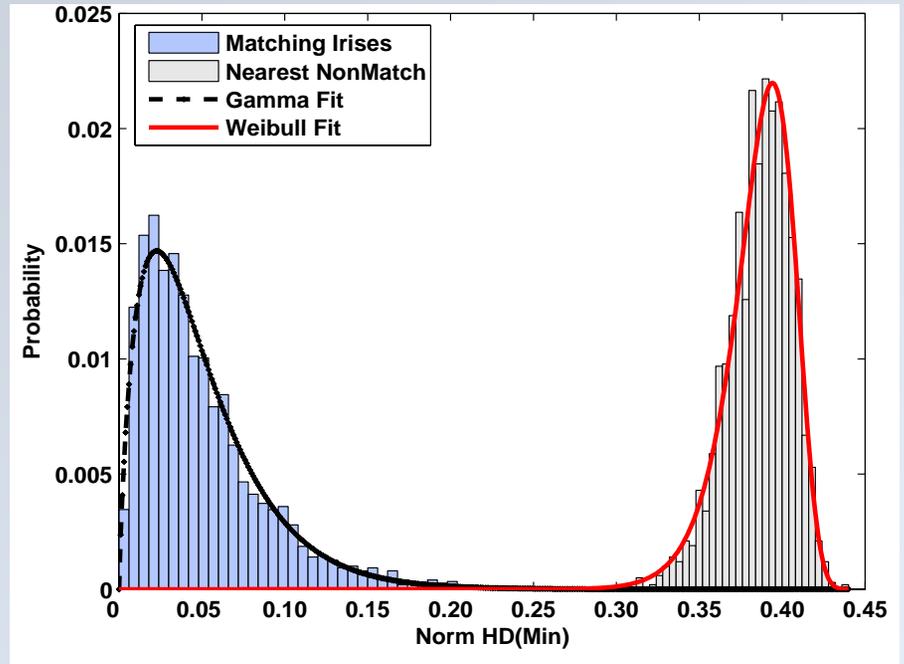
Test Datasets

Dataset	Number of Classes	Enrol Images per class	Test Images per Class	Total
CASIA	308	3	Rest	2156
Bath	150	3	Rest	2955

Results



Receiver Operating Characteristic Curves

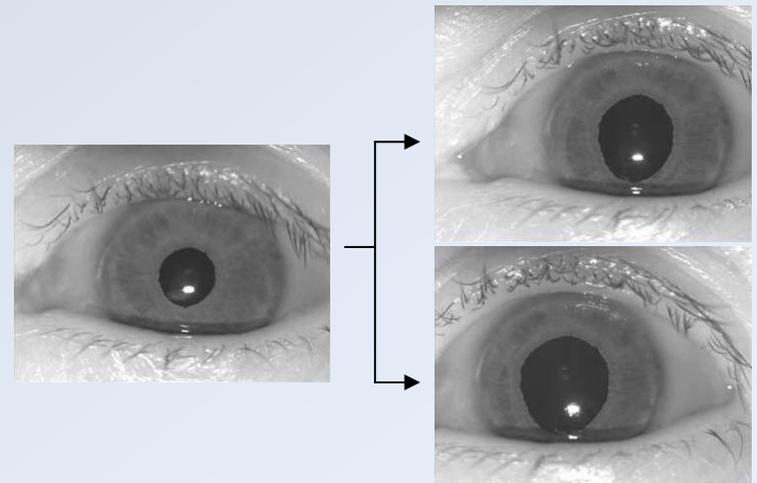
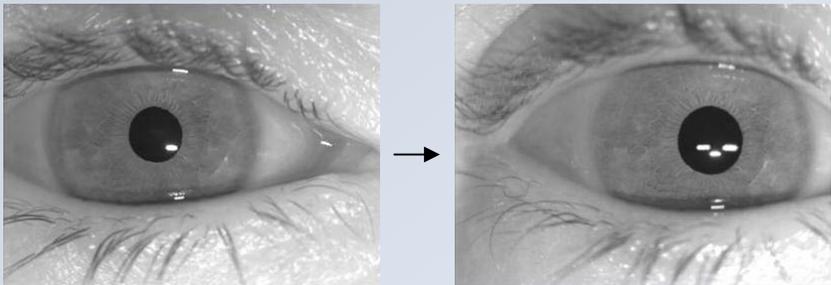


EER = 2.6×10^{-4} and Falling

Method	Feature Extraction (ms)	Matching (ms)	Total (ms)
Daugman	422	31	453
Tan	125	68	193
Monro	45	31	86

Ongoing & Future Work

- **More Iris Image Collection**
- **Iris Quality Metrics**
- **Novel Localization methods**
- **Fast Searching and Matching**
- **Rotation Invariance**
- **Alternative Iris Transforms**
- **Iris Variation Simulation**
- **Liveness Detection**
- **Effect of Medical Conditions**
- **Spoofing Countermeasures**



Acknowledgements

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Questions ?

